

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/554,188	TATSUMI ET AL.	
		Examiner	Art Unit	Page 1 of 2
		ELMITO BREVAL	2889	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
*	B	US-6,445,114 B1	09-2002	Kurokawa et al.	313/310
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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